

Notice of References Cited	Application/Control No. 10/567,747		Applicant(s)/Patent Under Reexamination TAKEDA ET AL.	
	Examiner HELEN SHIBRU		Art Unit 2621	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,923,220	07-1999	Honma, Hiroshi	331/17
*	B	US-5,966,387	10-1999	Cloutier, Leo	370/516
*	C	US-2005/0259952	11-2005	Gotoh et al.	386/046
*	D	US-2005/0175322	08-2005	Demas et al.	386/095
*	E	US-2004/0165867	08-2004	Seo et al.	386/096
*	F	US-2004/0055013	03-2004	Ishioka et al.	725/089
*	G	US-2002/0076196	06-2002	Nagata et al.	386/46
*	H	US-2002/0063796	05-2002	Min, Kyung Pa	348/523
*	I	US-7,705,652	04-2010	Jang, Kyungwoon	327/299
*	J	US-7,702,056	04-2010	Kaizuka, Masao	375/371
*	K	US-7,315,622	01-2008	Mani et al.	380/210
*	L	US-7,230,652	06-2007	Demas et al.	348/512
*	M	US-6,731,658	05-2004	Inazumi et al.	370/537

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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